

# Status of PID detectors at BigRIPS

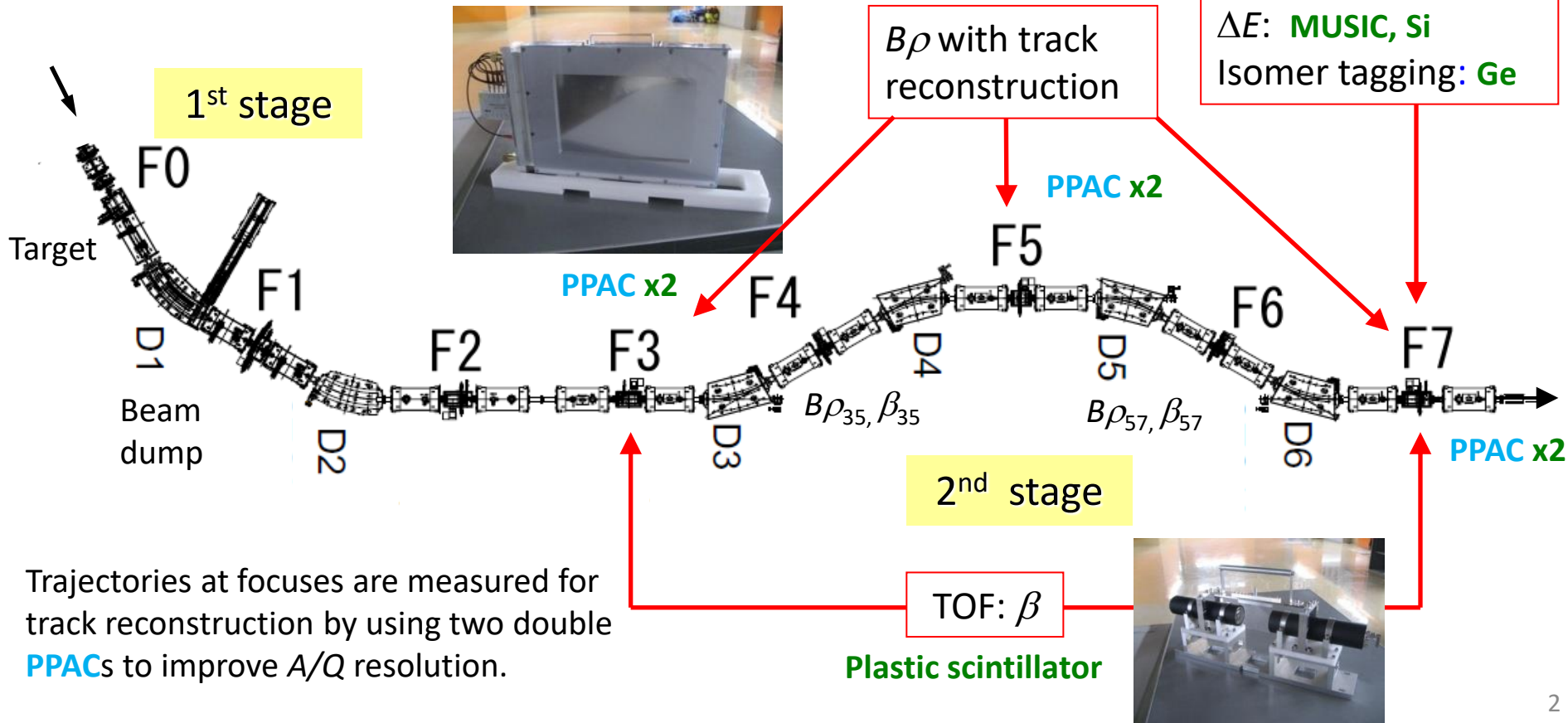
H. Sato, Detector team, RNC

# PID detectors at BigRIPS

Particle identification → TOF- $B\rho$ - $\Delta E$  method with track reconstruction

TOF,  $B\rho$ ,  $\Delta E$  →  $Z$ ,  $A/Q$

TOF: Time of flight  
 $B\rho$ : Magnetic rigidity  
 $\Delta E$ : Energy loss



# PPAC

Parallel Plate Avalanche Counter : PPAC

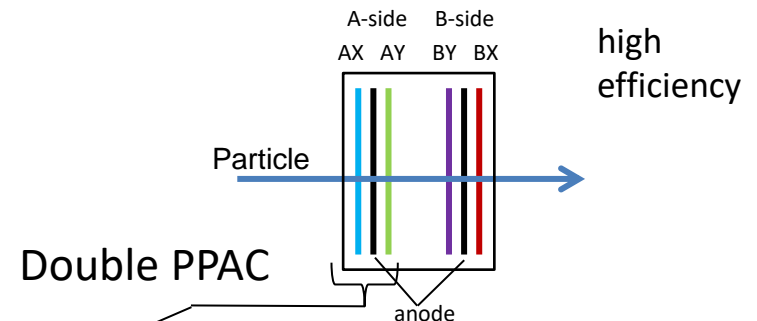
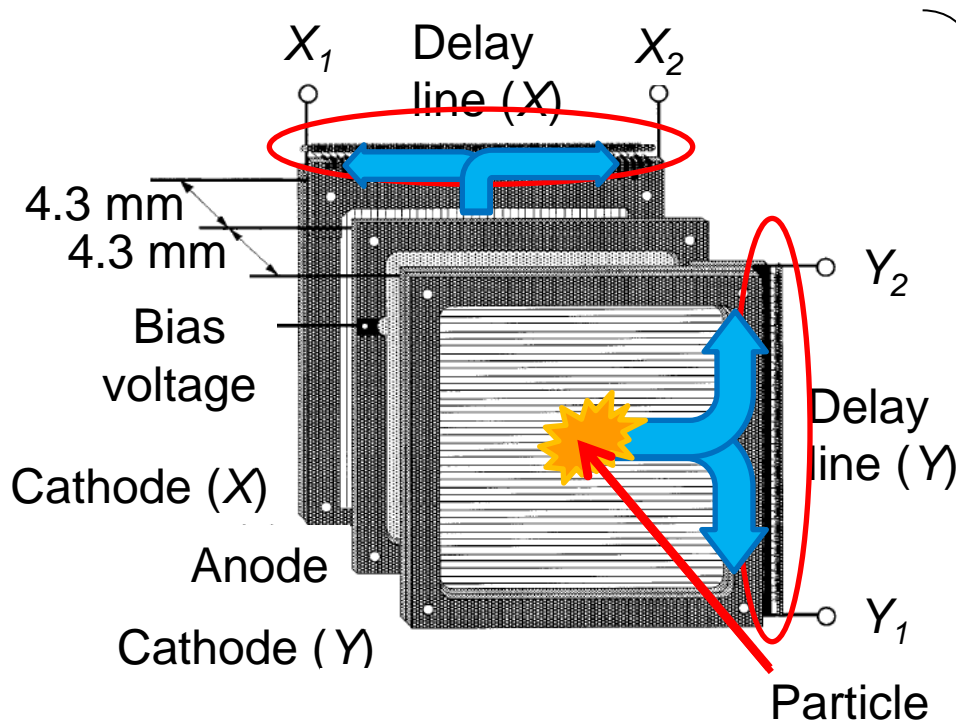
→ 2D position sensitive detector

- isobutane ( $C_4H_{10}$ ), 10 Torr
- $\sim 150V/mm$  electric field
- Electron avalanche

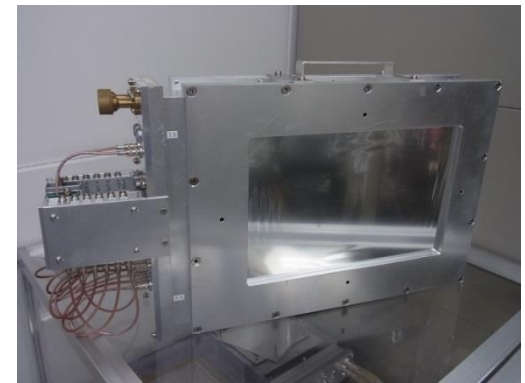
H. Kumagai et al., NIMB 317(2013)717-727.

+

**Delay-Line read-out**



240x150 double PPAC



# Today's items

## Recent topics on the PPAC

1. Discharge problem
  - ✓ Change of the material of the electrode
  - ✓ Development of the anti-discharge unit
2. Endurance test with high-rate beams
  - ✓ Efficiency
  - ✓ Position resolution
3. Fabrication of the electrodes
  - ✓ Clear strip gap
  - ✓ Damage problem



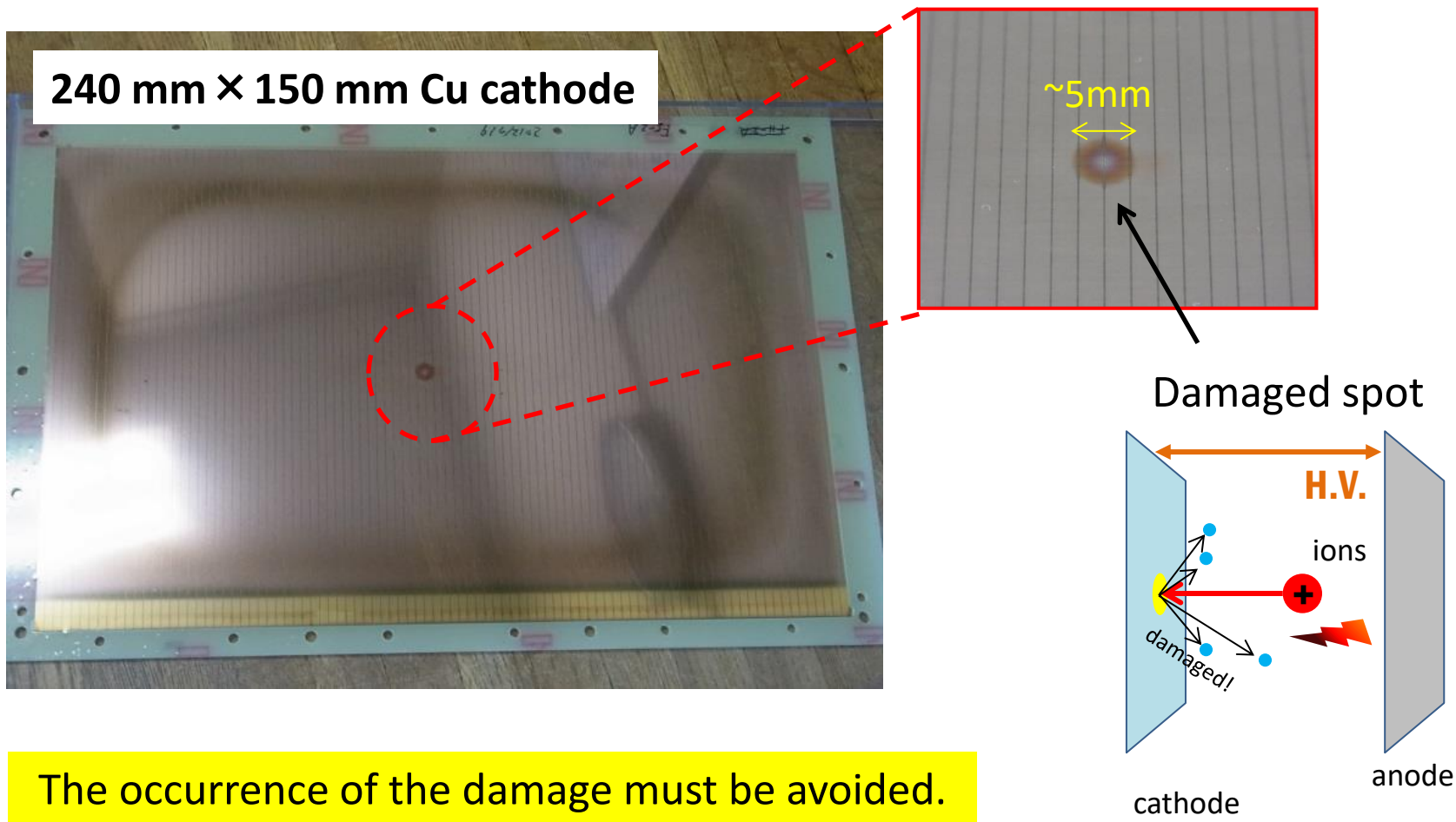
# **1. Discharge problem**

# 1. Damage due to discharge

Electrical discharge sometimes occur with several tens of kHz of beams.

Trip of H.V. modules frequently happens.

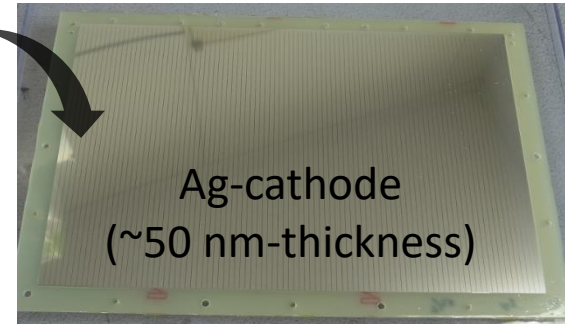
Damage on the cathode electrodes can be seen.



# Change the electrode materials

The occurrence of the discharge depends on the material of electrodes.

Au, Al, Cu → **Ag**



Empirically, silver electrode is more tolerant to the discharge than the others.

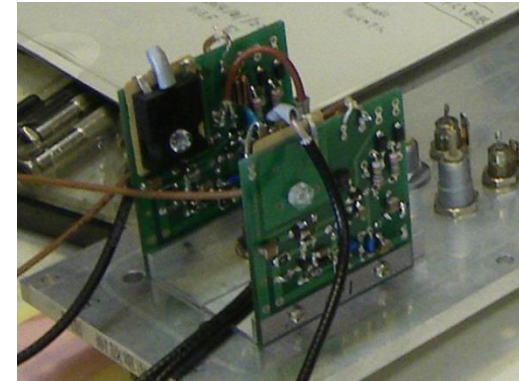
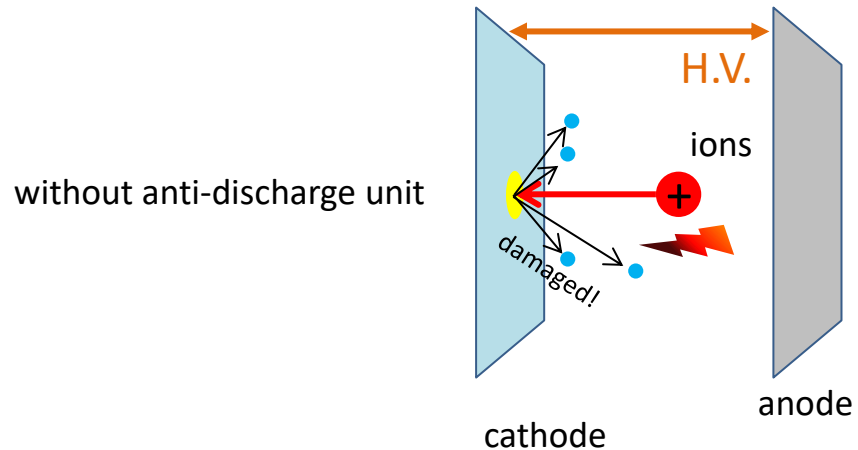


- Small electrical resistivity : Al > Au > Cu > **Ag**
- Large thermal conductivity : Al < Au < Cu < **Ag**

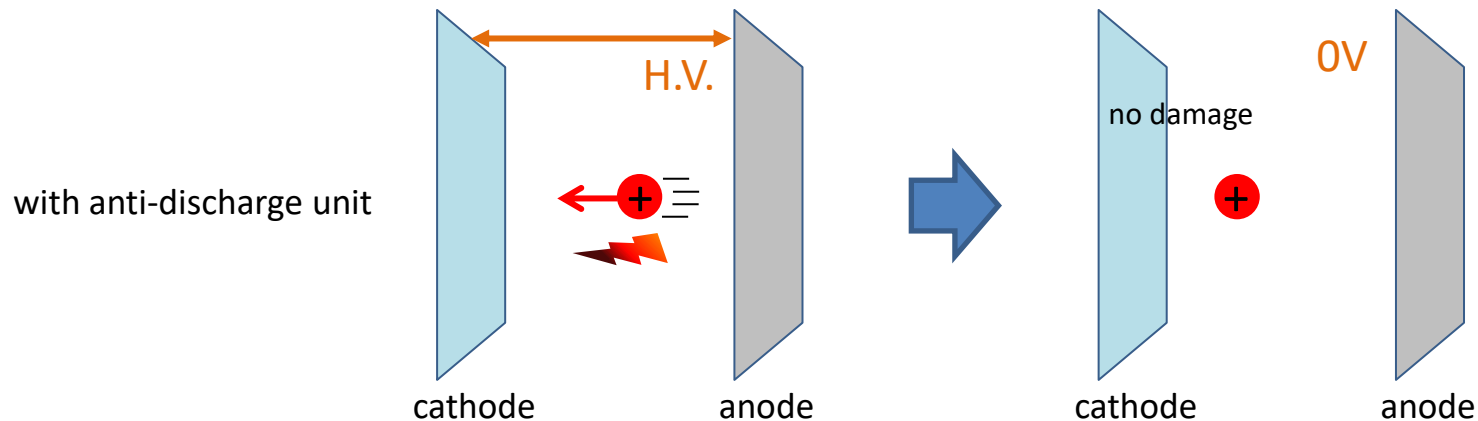
|           | Resistivity [ $\mu\Omega$ cm] |             | Thermal conductivity [ $\text{W m}^{-1} \text{K}^{-1}$ ] |            |
|-----------|-------------------------------|-------------|--|------------|
|           | 0°C                           | 100°C       | 0°C  | 100°C      |
| Al        | 2.5                           | 3.55        | 236  | 240        |
| Au        | 2.05                          | 2.88        | 319  | 313        |
| Cu        | 1.55                          | 2.23        | 403  | 395        |
| <b>Ag</b> | <b>1.47</b>                   | <b>2.08</b> | <b>428</b>   | <b>422</b> |

# Anti-discharge unit

Anti-discharge unit (ADU) is being developed by Kumagai-san.



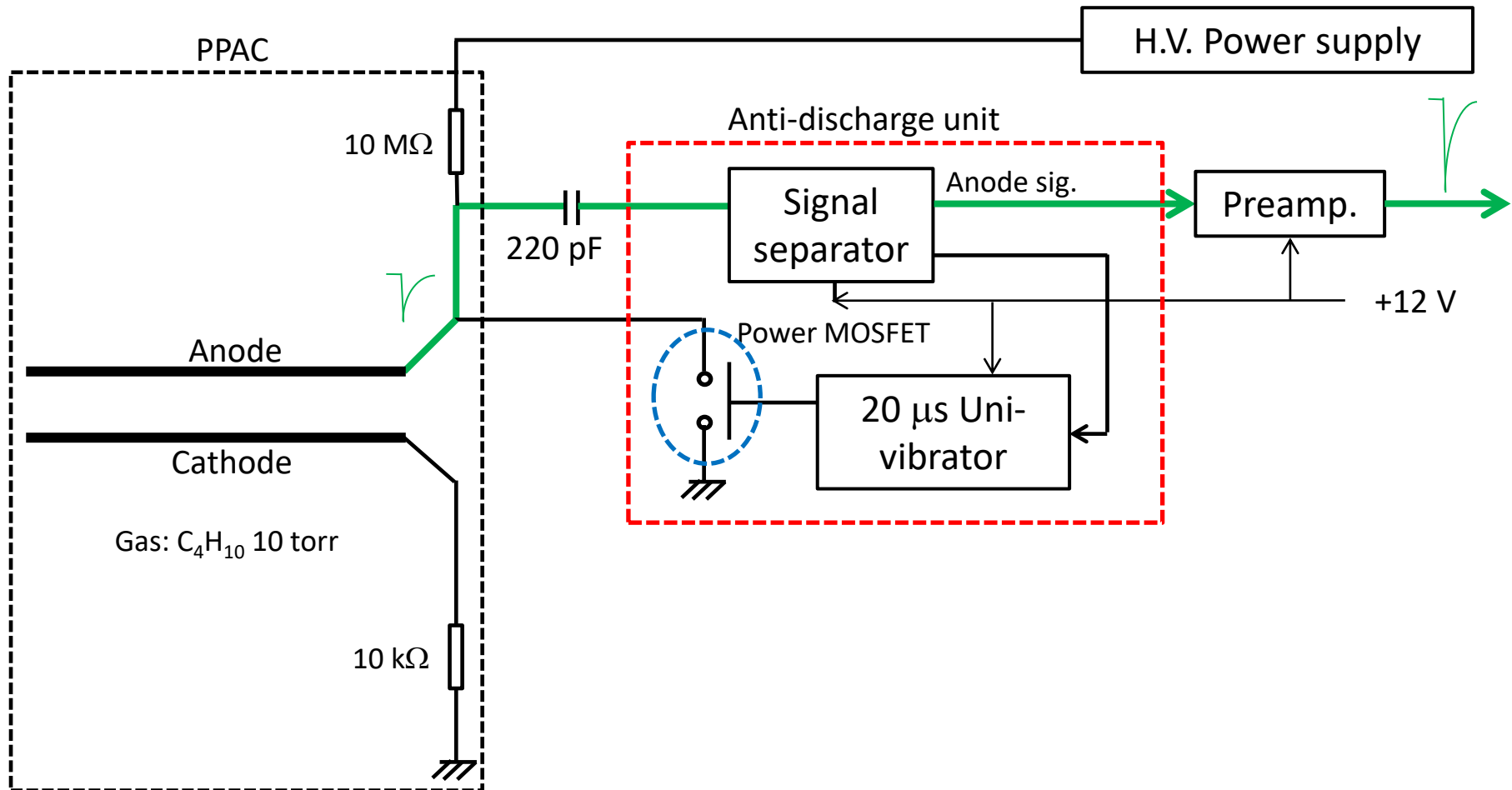
H.V. is forced to become 0V to stop the discharge before ions hit the cathode electrode.





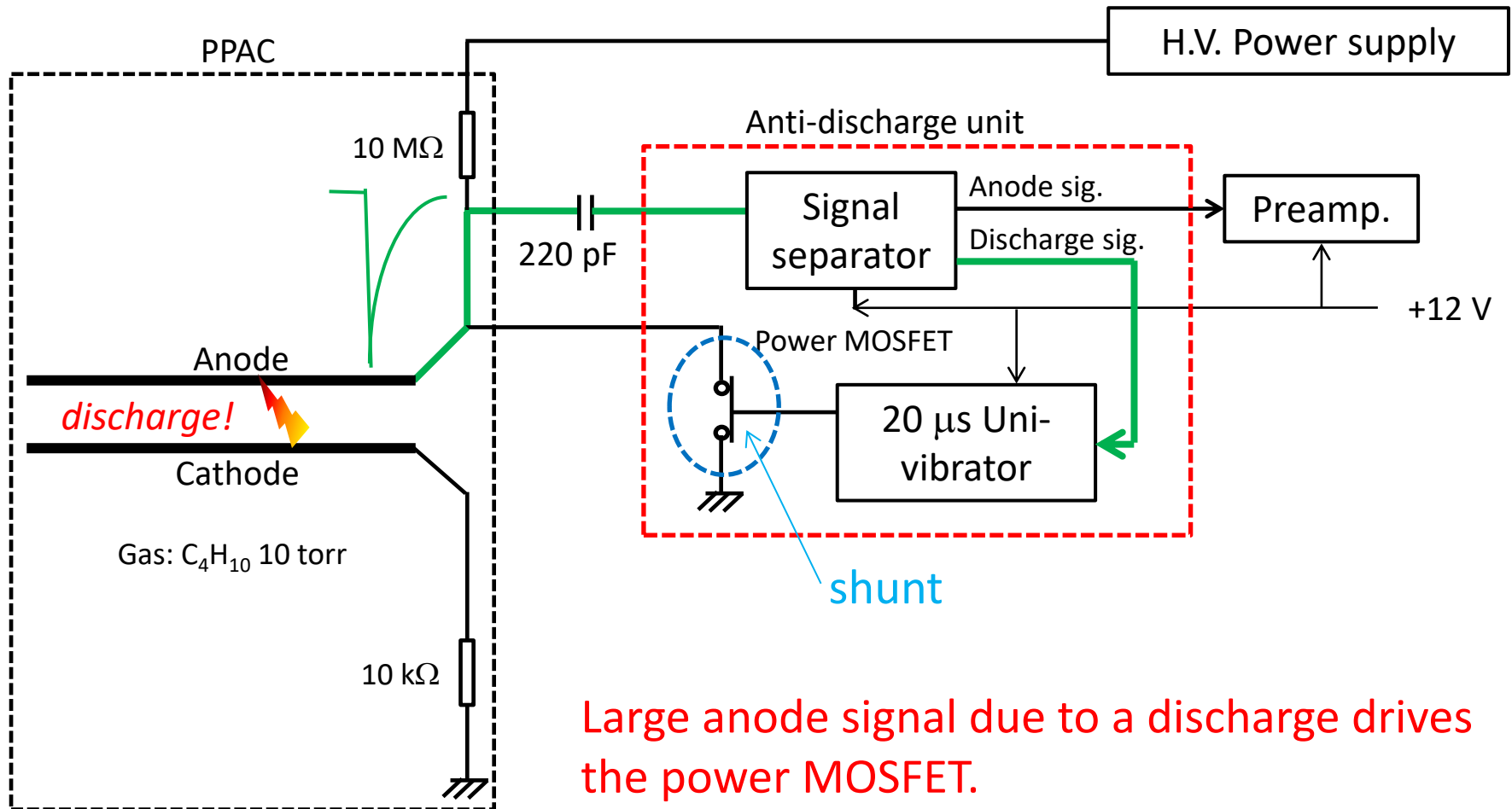
# Function of the ADU

No discharge



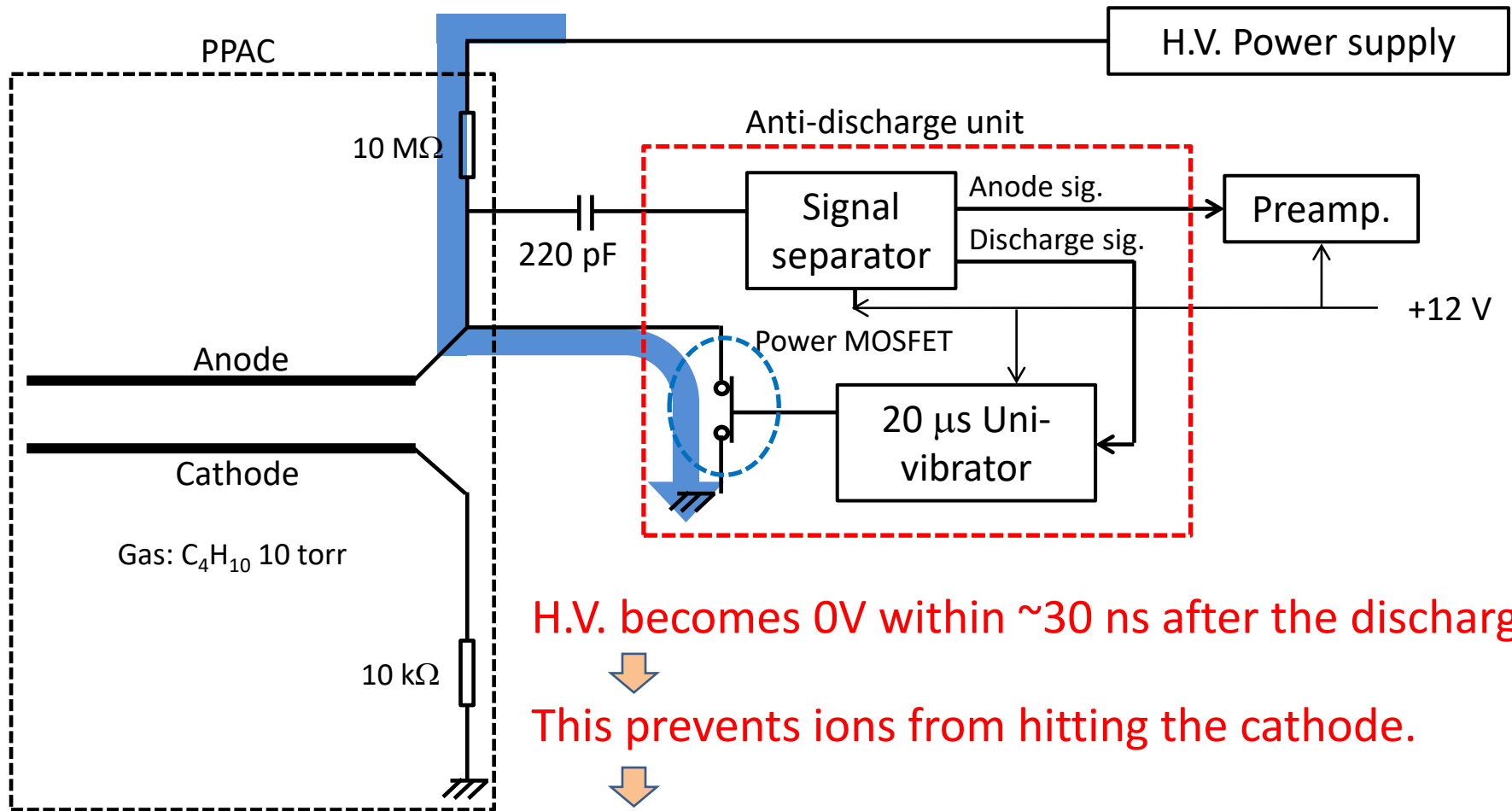
# Function of the ADU

Discharge occurs



# Function of the ADU

H.V. becomes 0V



H.V. becomes 0V within ~30 ns after the discharge.



This prevents ions from hitting the cathode.



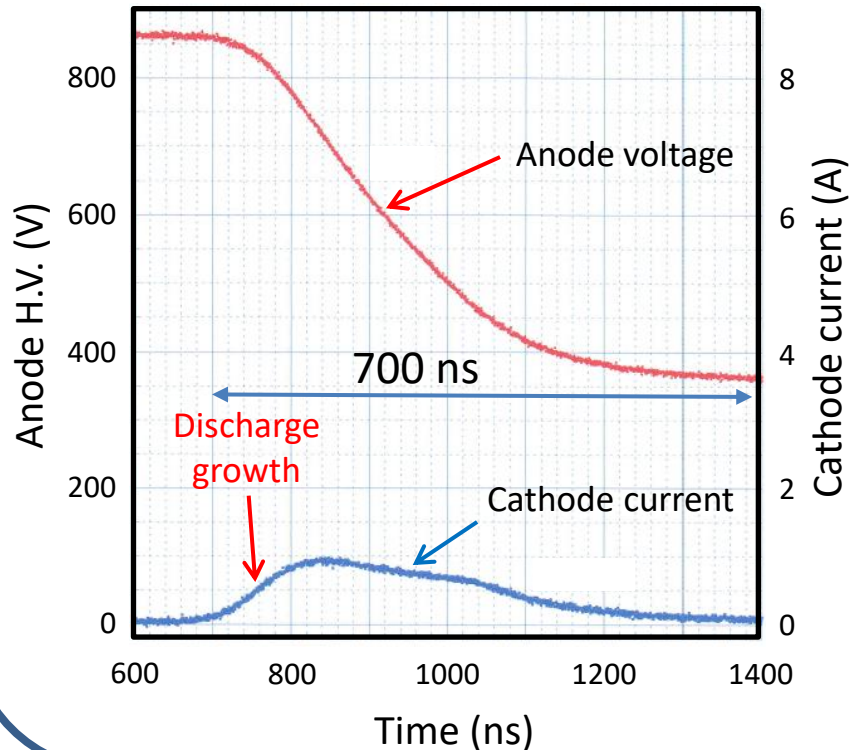
Reduce the damage on the cathode electrodes.

( H.V. recovers in ~5 ms. )

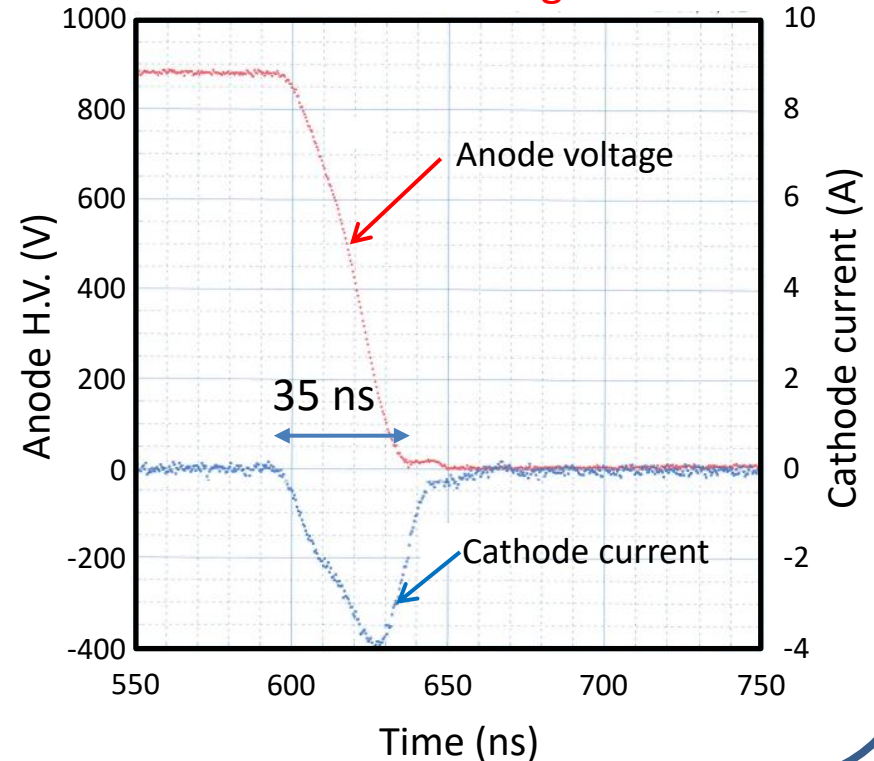
# Test of the ADU

Discharge was induced using  $^{241}\text{Am}$ -alpha by applying the too large bias voltage, intentionally.

Without anti-discharge unit



With anti-discharge unit



The anode voltage (H.V.) was forcibly 0V by the anti-discharge unit.



Prevent damages on the cathode electrodes

## **2. endurance test with high-rate beams**

## 2. Test with high-rate beams

### ➤ Ag electrodes



*First test with RI-beams for Ag electrode*

- 2012 ● ~160 kHz of Ni ( $Z=28$ ) ions for 1 hour
- 2014 ● ~50 kHz of Cs ( $Z=55$ ) ions for 2.5 days.
- ~70 kHz of  $Z\sim 60-70$  ions for ~5 hours.
- Apr. 2015 ● ~400 kHz of Sn ( $Z=50$ ) ions for ~40 min.

**No damage**

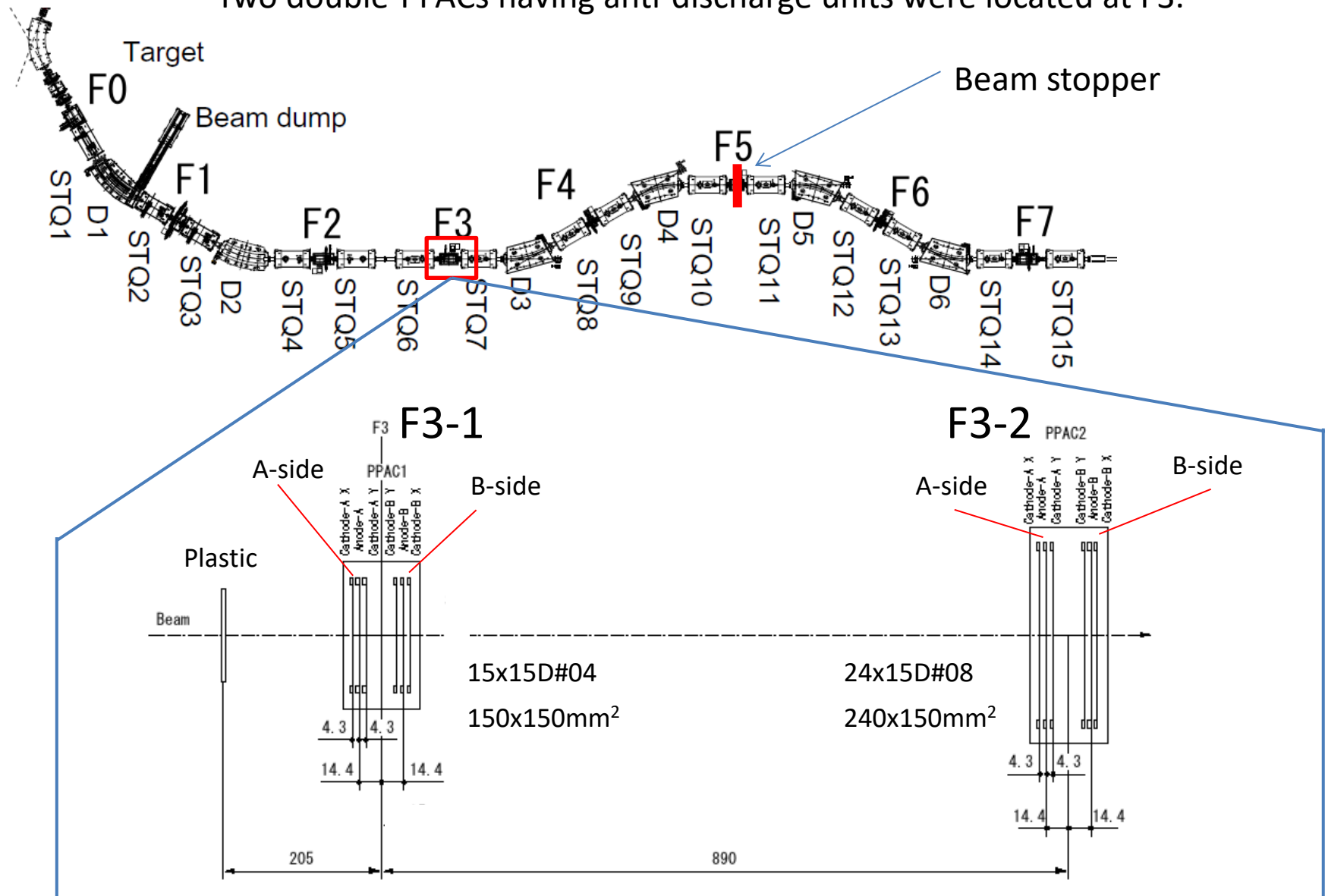
### ➤ Anti-discharge unit



An endurance test of the PPAC against high-rate beams ( $Z\sim 50$ ) was carried out in Nov. 2015.

# Location of the PPACs

Two double-PPACs having anti-discharge units were located at F3.

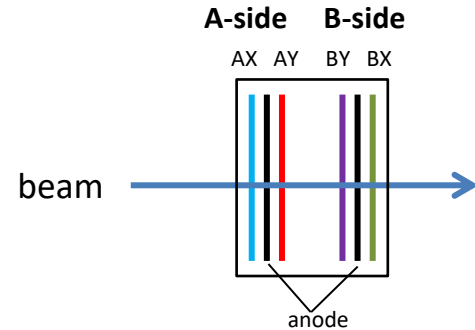


# RI beams

Z~50 beams were used.

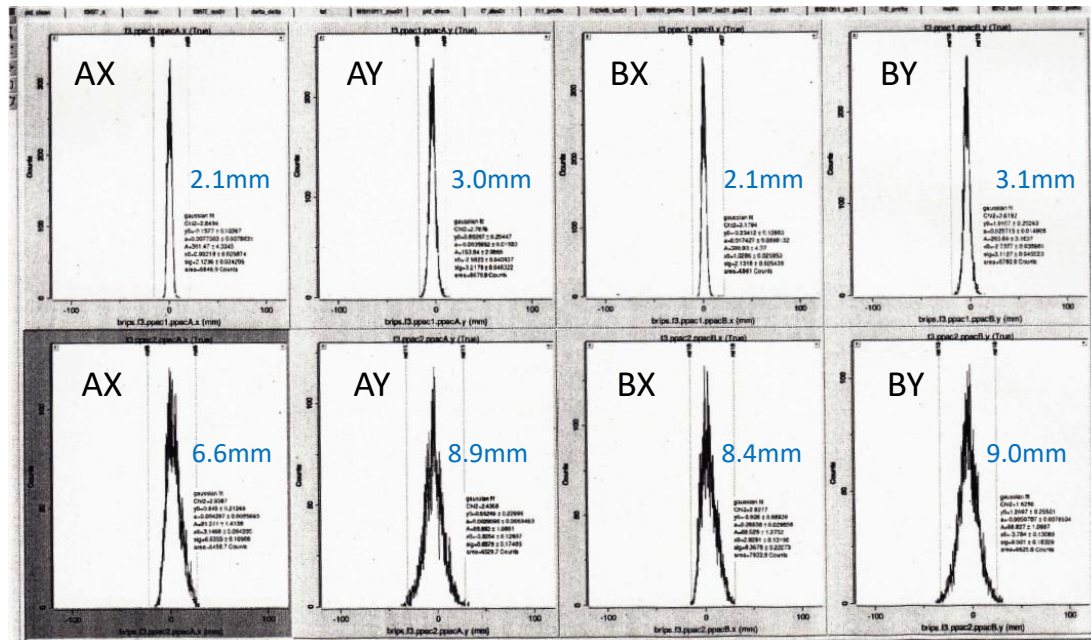
$^{132}\text{Sn}$  (Z=50) purity: 6%  
 $^{133}\text{Sb}$  (Z=51) purity: 20%  
 $^{134}\text{Te}$  (Z=52) purity: 31%  
 $^{135}\text{I}$  (Z=53) purity: 12%

E~220 MeV/u @F3



Beam spot ( $\sigma$ )

@F3-1



@F3-2

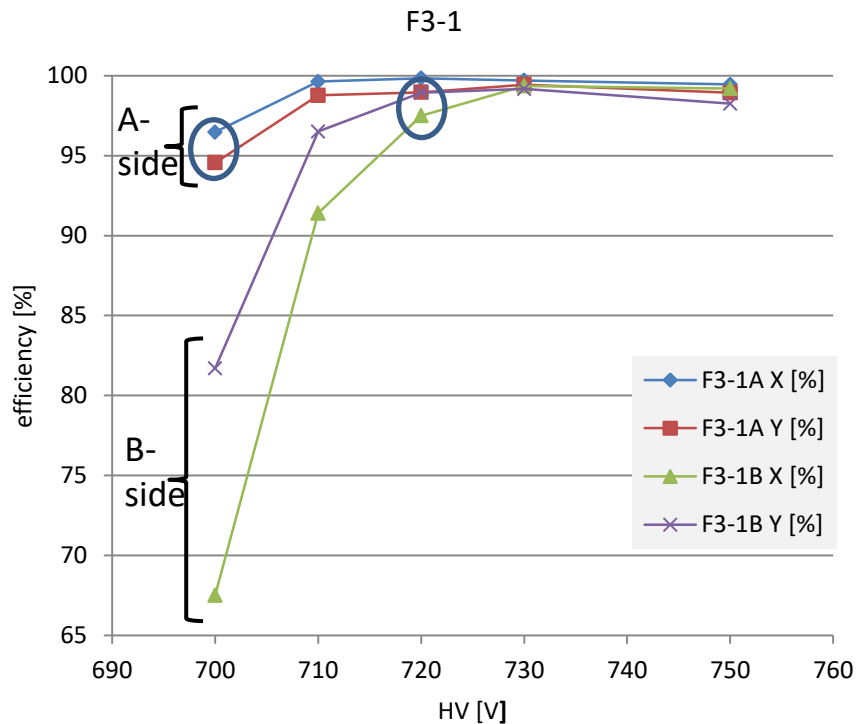
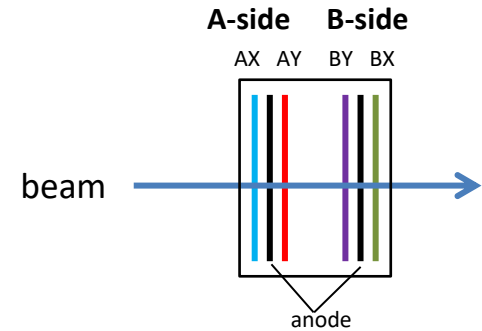


# Bias voltage adjustment

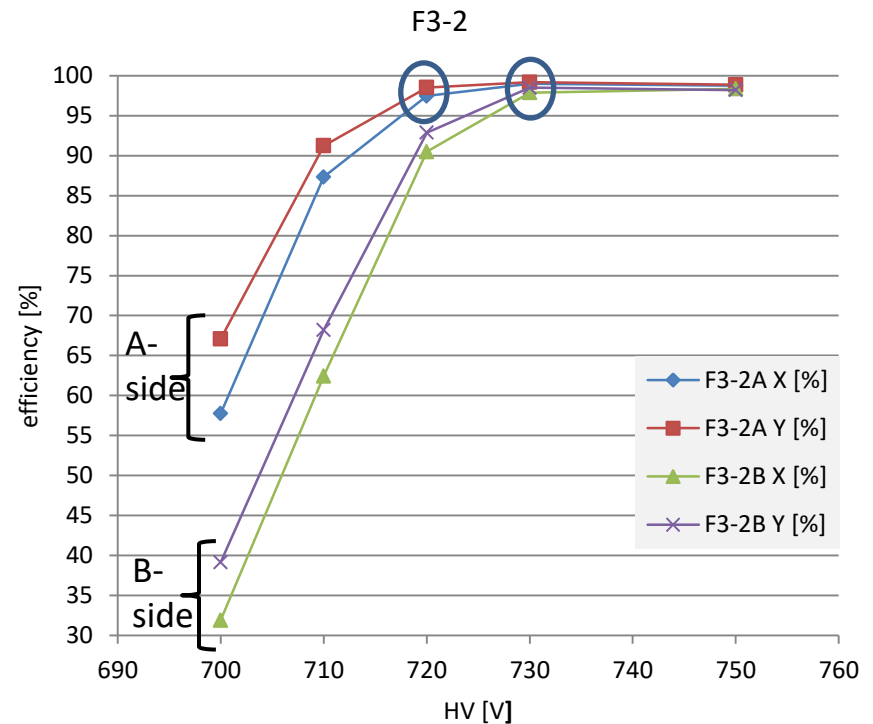
Before irradiating the PPACs with intense beams, the HV dependence of detection efficiency for each cathode was measured with a 1kHz beam.



The bias voltage was adjusted for all cathodes so as to realize the efficiency of ~95% in order to reduce unnecessary voltage.



F3-1 A-side:700V  
B-side:720V



F3-2 A-side:720V  
B-side:730V

# Beam rate

Rate of the beams @F3 was increased step by step as follows:

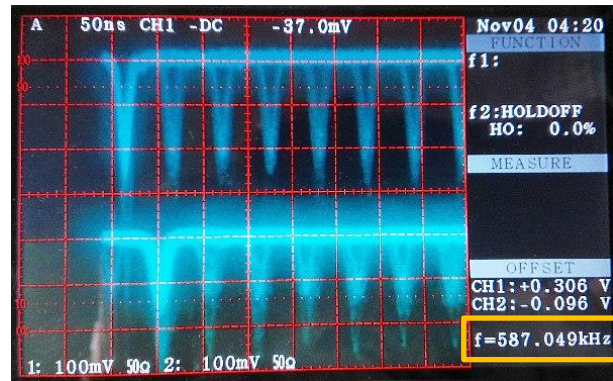


# Results: Endurance

- 600kcps 70min → **No trip** of HV modules for both PPACs

F3-1A anode

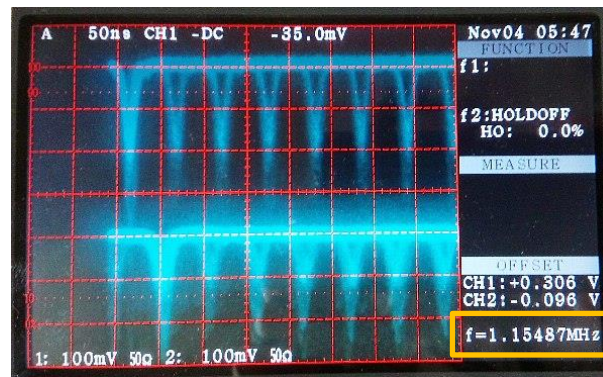
y2



- 1 Mcps 60min → **No trip** of the HV modules for both PPACs

F3-1A anode

y2



# Results: Efficiency

Tendency of the total efficiency was measured.

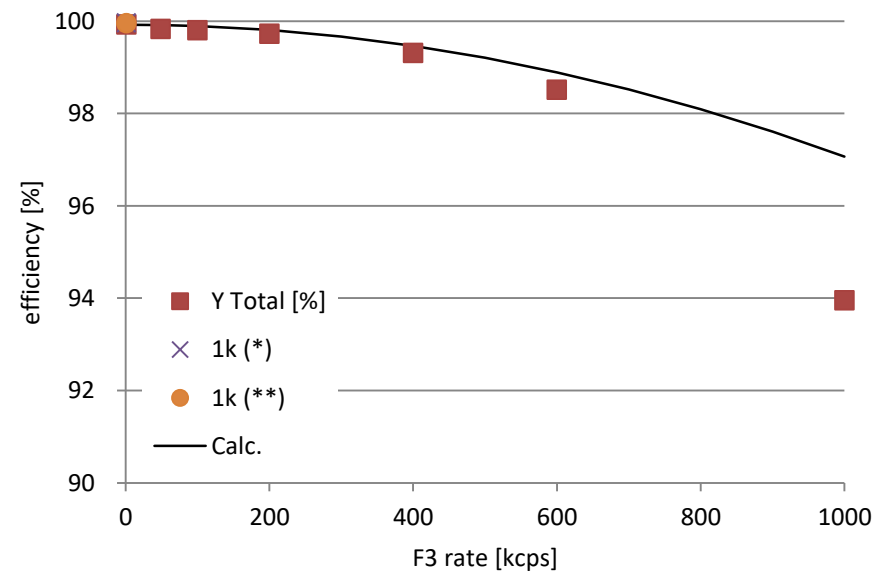
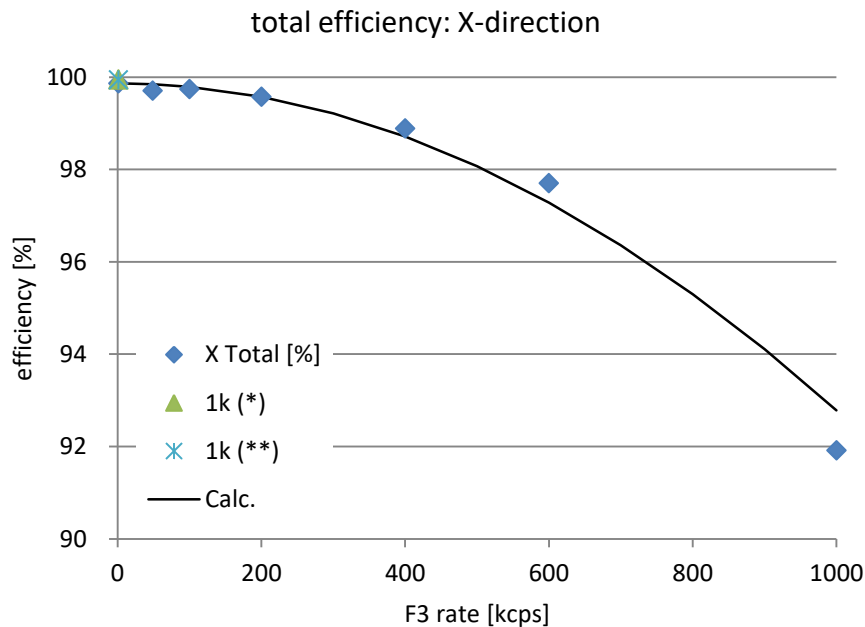
$$Eff_{Xtotal} = \{1 - (1 - Eff_{F3-1AX})(1 - Eff_{F3-1BX})\} \{1 - (1 - Eff_{F3-2AX})(1 - Eff_{F3-2BX})\}$$

Total efficiency
Efficiency of each cathode

Order of the measurements

| rate [kcps] | X Total [%] | Y Total [%] |
|-------------|-------------|-------------|
| 1.3         | 99.86       | 99.92       |
| 49          | 99.70       | 99.83       |
| 100         | 99.74       | 99.80       |
| 200         | 99.57       | 99.72       |
| 400         | 98.89       | 99.30       |
| 600         | 97.70       | 98.51       |
| 1 (*)       | 99.95       | 99.96       |
| 1000        | 91.92       | 93.93       |
| 1 (**)      | 99.94       | 99.95       |

total efficiency: X-direction      total efficiency: Y-direction



The efficiency obtained with 1k<sup>(\*)</sup> and 1k<sup>(\*\*)</sup> just after high-rate beams reproduce the values obtained with the 1.3k (first run).

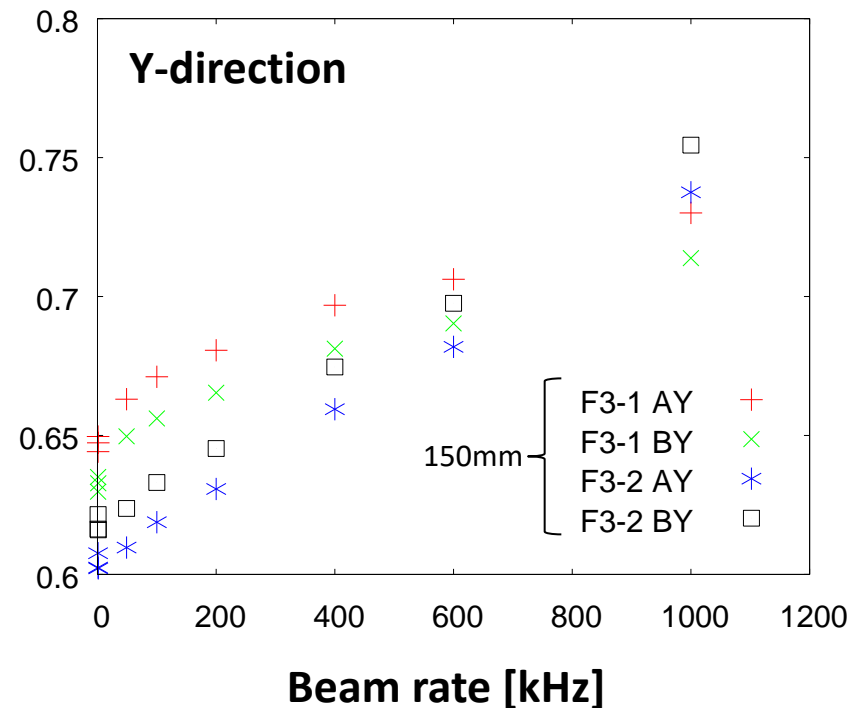
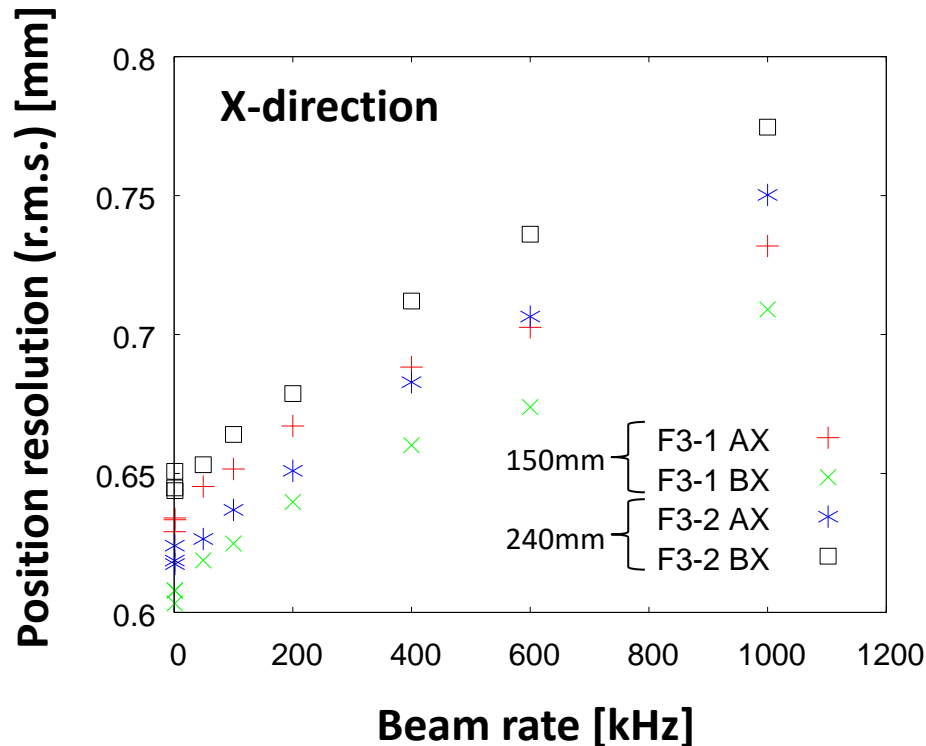
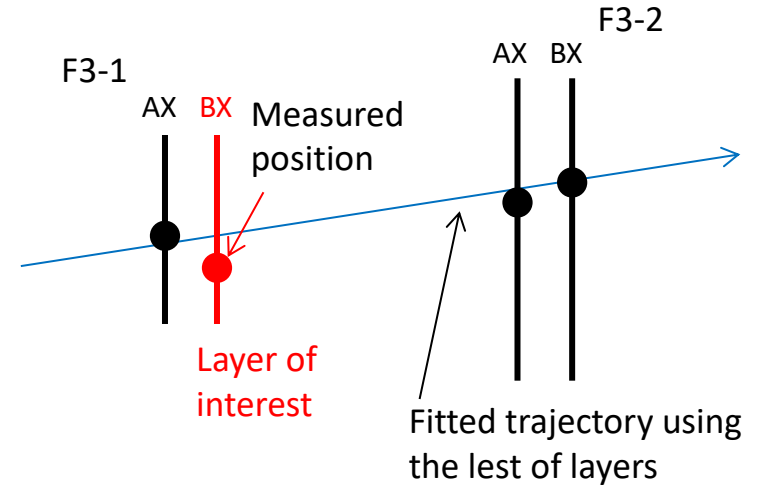
The tendency of the efficiency change can be explained by the dead time of the PPAC: delay time is 192 ns for X and 118 ns for Y.



Electrodes were not damaged with 1Mcps beams for 60 minutes.

# Results: Position resolution

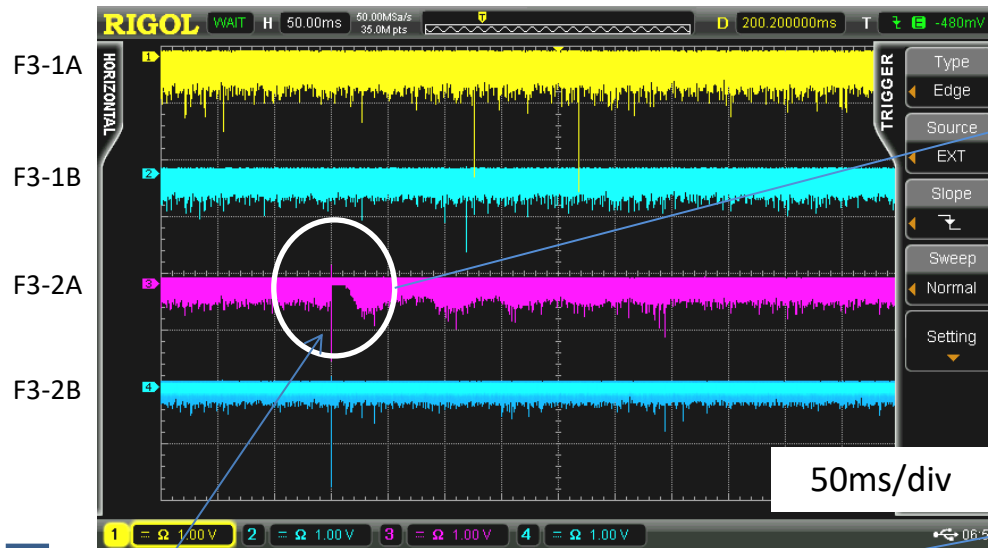
The position resolution is deduced for the layer of interest with respect to the trajectory that was obtained by fitting the measured positions using the rest of layers.



# Results: action of the ADU

We increased the bias voltage of F3-2A up to 750V @1MHz beam, and a discharge happened on F3-2A.

Signal from X cathodes



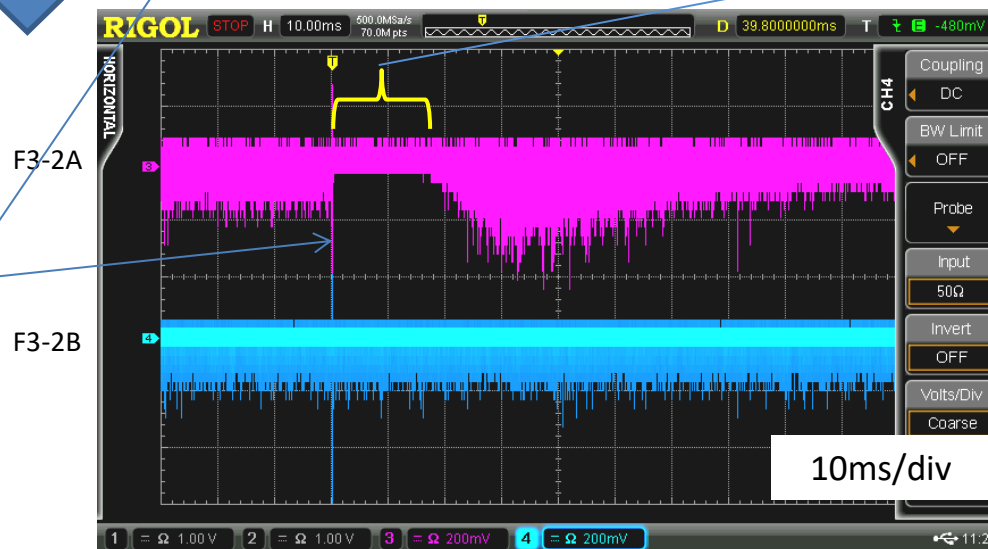
The anti-discharge unit was operated.

Bias voltage was shutdown and recover.

enlarged view



discharge

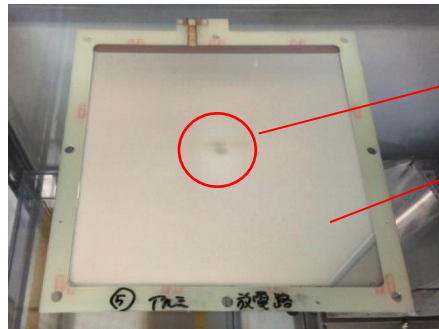


16ms

# Unresolved discharge problems

From the data of the efficiency, we found that the electrodes were not damaged. So, we think that the combination of the Ag electrode and the ADU is effective.

- Damage on the **anode** appears because the lifetime of the cathode becomes longer by using the anti-discharge unit.
- ✓ The ADU cannot stop the electrons which are running to the anode.
- ✓ We prepared the anodes which have thicker Ag layer (50nm → 100nm).
- ✓ We will test them on the beamline.



Same kind of damages are seen in the case of Ag.

- Discharge happens with high-rate **light beams** because higher bias voltage should be applied for enough efficiency.

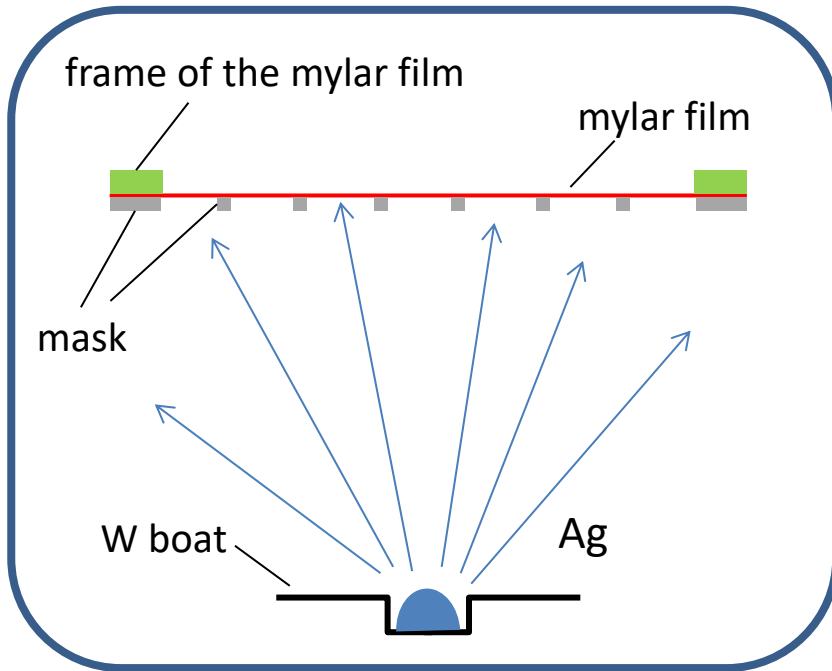
# **3. Fabrication of the electrodes**



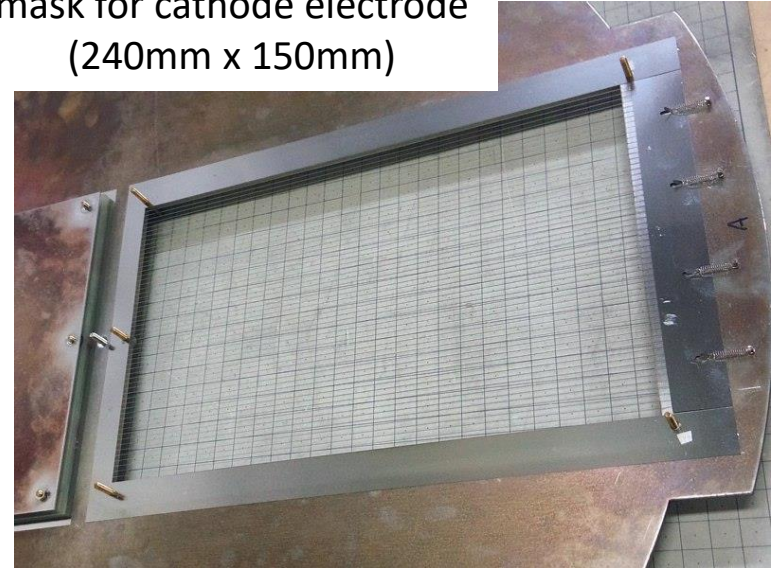
# 3. Fabrication of the electrodes

Ag electrodes are fabricated by using vacuum evaporation.

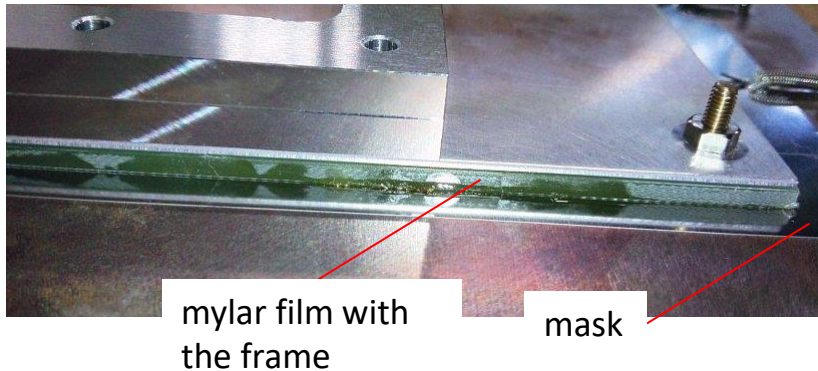
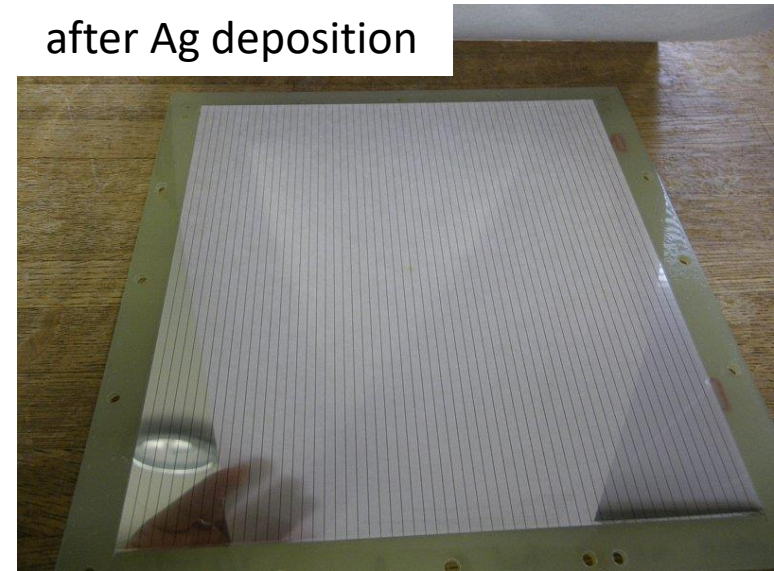
Side view



mask for cathode electrode  
(240mm x 150mm)



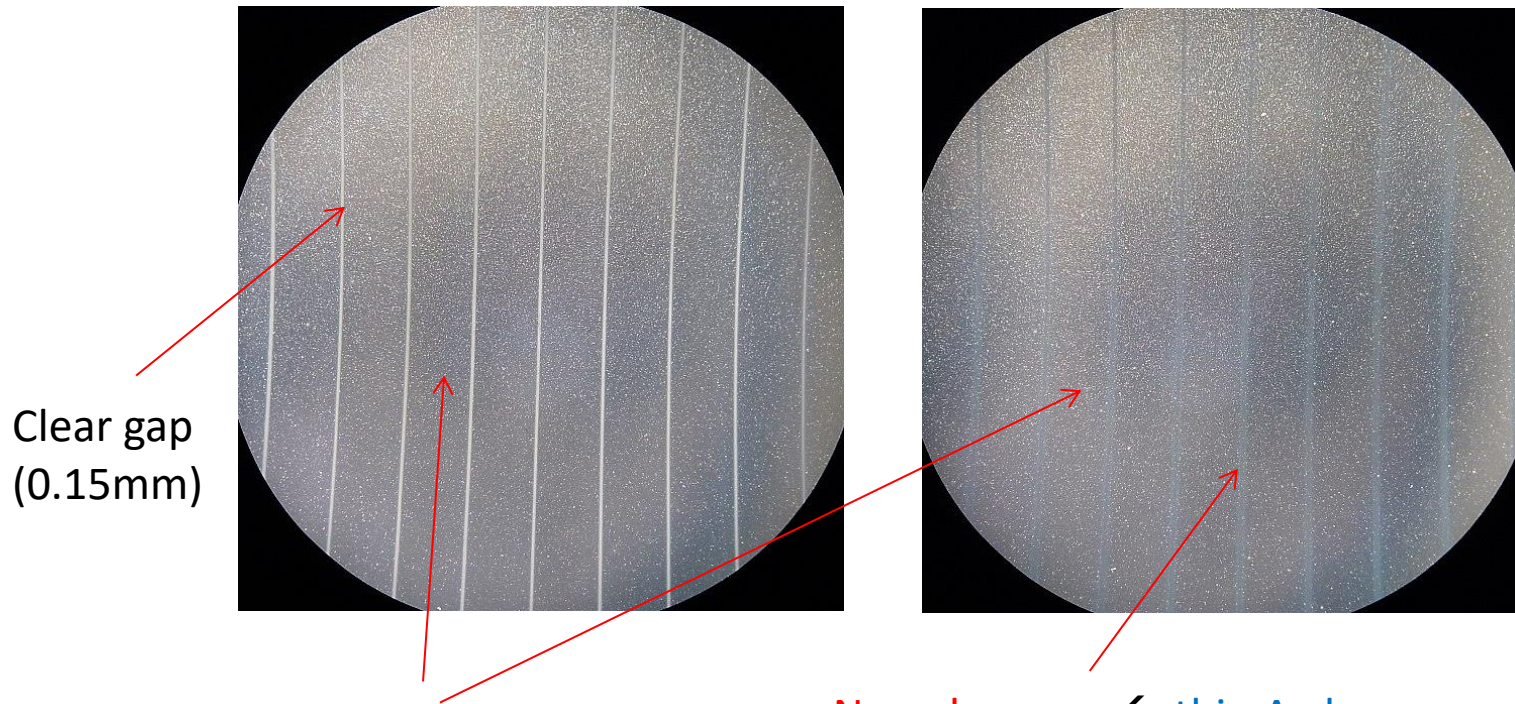
after Ag deposition



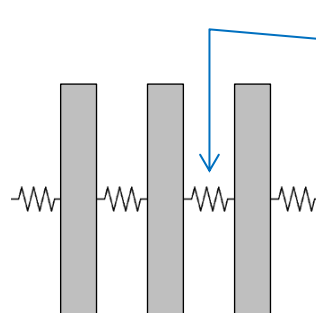
# Non-clear strip gaps

Sometimes, non-clear strip gaps are seen after depositing Ag.

Microscopic view



Non-clear gap ← thin Ag layer



Each strips are connected !



Such electrode cannot be used !



# Non-clear strip gaps

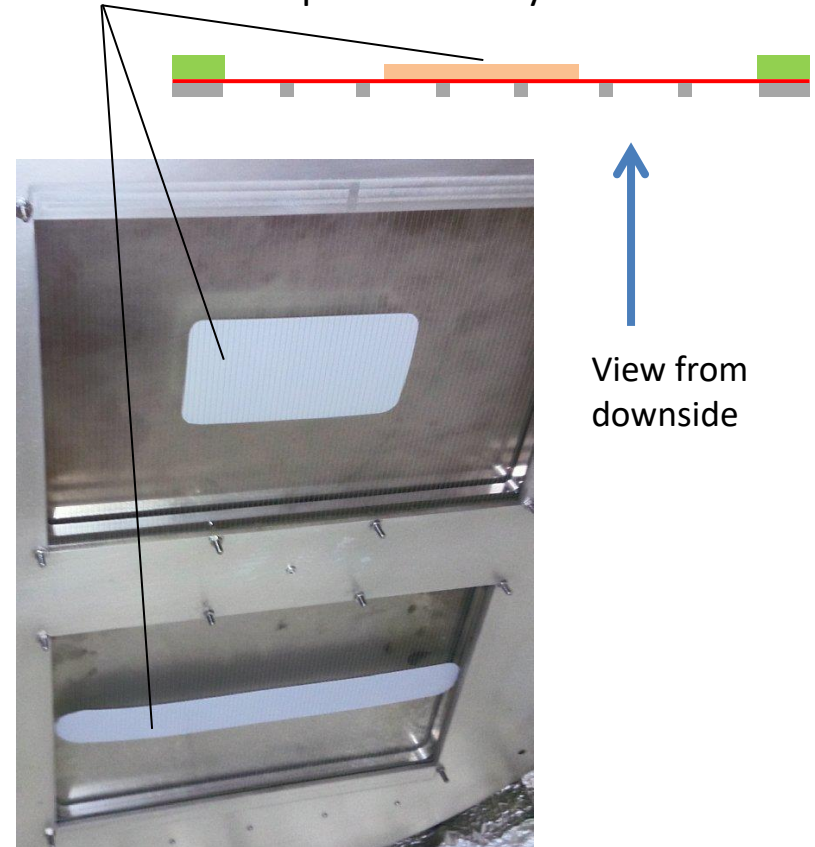
Non-clear strip gaps comes from the imperfect contact between the mylar film and the mask wire.



- Add the spring to apply more tension to the mask wire.



- Silicon rubber is put on the mylar film.

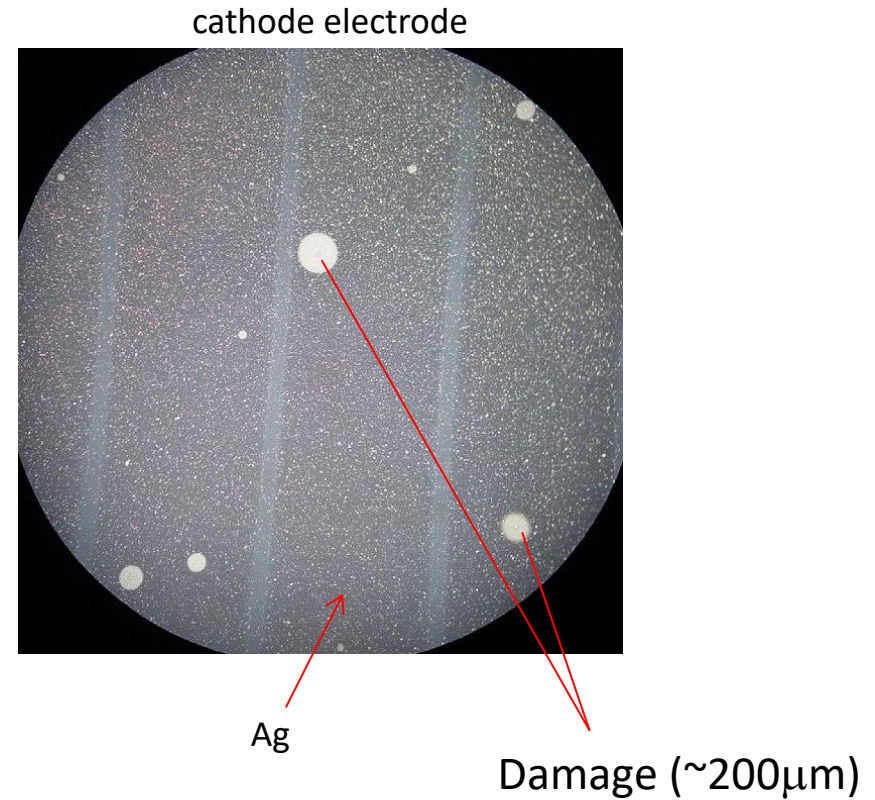
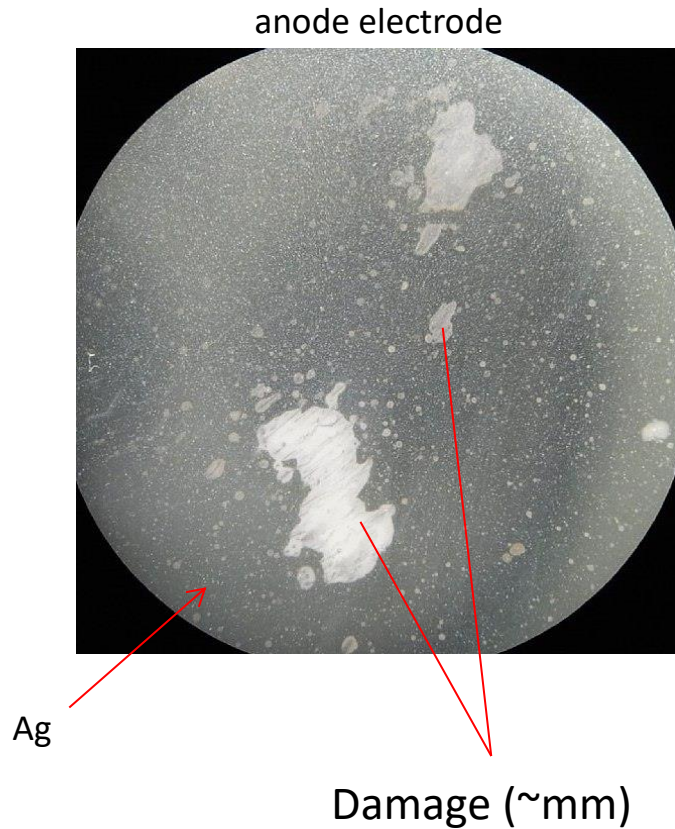


Production yield: ~50% → 100%!

# Damage on the Ag films

After depositing Ag on the mylar film, sometimes damages (colored arer of the Ag) has been seen.

## Examples

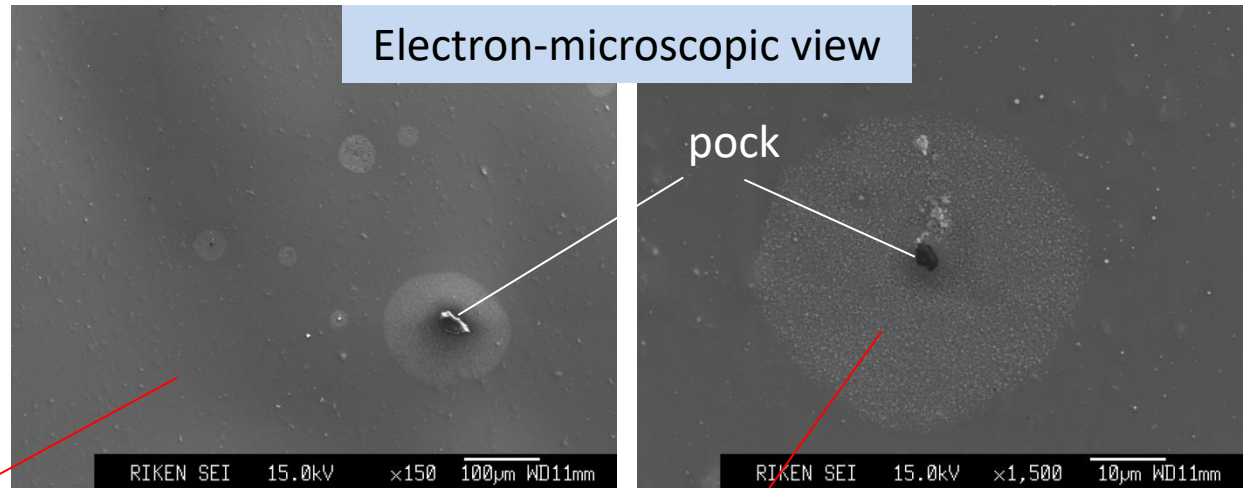


- ✓ Sometimes, they appear immediately after finishing the deposition.
- ✓ Sometimes, they appear several days after.

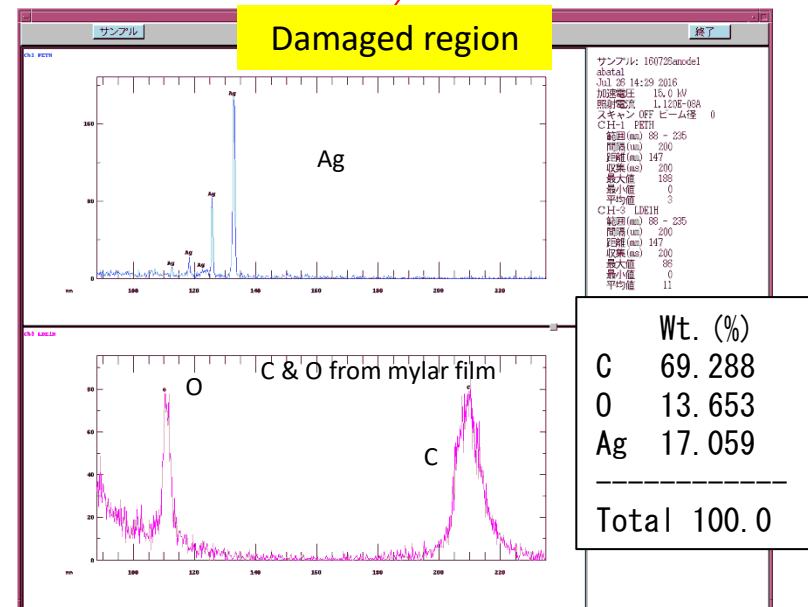
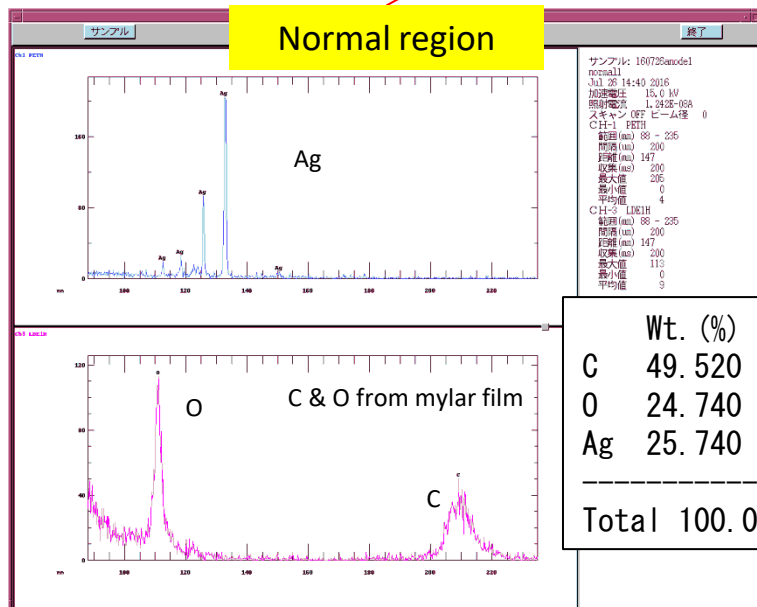
# Component analysis with EPMA

The component analysis of the damaged area was done by using Electron Probe Micro Analyzer.

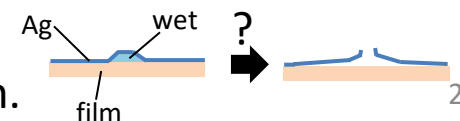
Electron-microscopic view



Spectrum of character X-rays



There are no contaminants in the damaged area.  
We consider that the reason of the damage is due to the wet on the film.



# Summary

Development of the PPAC is reported.

1. Material of the electrodes was changed (Au, Cu, Al → Ag).
2. Anti-discharge unit is being developed by Kumagai-san.
3. PPAC worked with 1MHz beams ( $Z \sim 50$ ) for 60min.
4. There are unresolved problems: one is the damage on the anode and another is the discharge with high-rate light beams.
5. Fabrication technique for Ag electrodes has been modified.  
Investigation of the damage on the Ag films is continued. (We got a new air conditioner in this summer !!)